

ABSTRACT OF THE DISCLOSURE

An accelerated test method for testing an integrated circuit is described.

The accelerated test method has the following steps. First, test vector data is

5 taken as input to the integrated circuit to produce response data as output.

Next, a one-way-hash function is used to transform the response data into a test message digest. Next, the test message digest is verified against a

standard message digest to determine whether the test message digest meet a predetermined requirement. The one-way-hash function is embedded as part

10 of the BIST circuit in the integrated circuit or implemented within automated test equipment.